

Notice of References Cited	Application/Control No. 10/046,224		Applicant(s)/Patent Under Reexamination NISHIOKA ET AL.	
	Examiner David G. Cervetti		Art Unit 2136	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,297,206	03-1994	Orton, Glenn A.	380/30
*	B	US-5,365,589	11-1994	Gutowitz, Howard A.	380/43
*	C	US-5,606,617	02-1997	Brands, Stefanus A.	380/30
*	D	US-5,987,133	11-1999	Aisaka, Kazuo	713/170
*	E	US-6,081,598	06-2000	Dai, Wei	380/28
*	F	US-6,236,729	05-2001	Takaragi et al.	380/286
*	G	US-6,353,888	03-2002	Kakehi et al.	713/168
*	H	US-2002/0044653	04-2002	Baek et al.	380/42
*	I	US-2003/0002662 A1	01-2003	Nishioka et al.	380/30
*	J	US-2003/0133567 A1	07-2003	Yajima et al.	380/30
*	K	US-6,697,488	02-2004	Cramer et al.	380/30
*	L	US-6,813,358	11-2004	Di Crescenzo et al.	380/280
*	M	US-6,859,533	02-2005	Wang et al.	380/28

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000216774 A	08-2000	Japan	ABE, MASAYUKI	H04L 09/32
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Dolve et al., Non-Malleable Cryptography, 2000, ACM.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/046,224		Applicant(s)/Patent Under Reexamination NISHIOKA ET AL.	
	Examiner David G. Cervetti		Art Unit 2136	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,640,454 A	06-1997	Lipner et al.	380/286
*	B	US-5,907,618 A	05-1999	Gennaro et al.	380/286
*	C	US-5,956,407 A	09-1999	Slavin, Keith R.	380/30
*	D	US-6,009,177 A	12-1999	Sudia, Frank Wells	713/191
*	E	US-6,091,819 A	07-2000	Venkatesan et al.	380/28
*	F	US-6,097,813 A	08-2000	Vanstone et al.	380/30
*	G	US-6,148,084 A	11-2000	Brands, Stefanus A.	380/279
*	H	US-6,212,277 B1	04-2001	Miyaji, Atsuko	380/30
*	I	US-2002/0001383 A1	01-2002	Kasahara, Masao	380/30
*	J	US-6,385,318 B1	05-2002	Oishi, Kazuomi	380/262
*	K	US-6,480,606 B1	11-2002	Kurumatani, Hiroyuki	380/30
*	L	US-6,651,167 B1	11-2003	Terao et al.	713/168
*	M	US-6,782,100 B1	08-2004	Vanstone et al.	380/28

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/046,224		Applicant(s)/Patent Under Reexamination NISHIOKA ET AL.	
	Examiner David G. Cervetti		Art Unit 2136	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,224,162 A	06-1993	Okamoto et al.	705/69
*	B	US-5,375,170 A	12-1994	Shamir, Adi	380/30
*	C	US-5,581,615 A	12-1996	Stern, Jacques	713/180
*	D	US-5,600,725 A	02-1997	Rueppel et al.	380/30
*	E	US-2002/0103999 A1	08-2002	Camnisch et al.	713/155
*	F	US-6,516,413 B1	02-2003	Aratani et al.	713/170
*	G	US-6,813,357 B1	11-2004	Matsuzaki et al.	380/279
*	H	US-2005/0091524 A1	04-2005	Abe et al.	713/200
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.